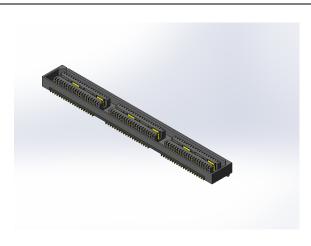
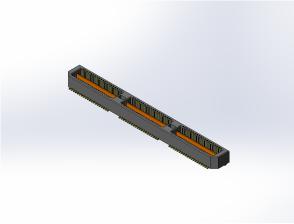


Project Number: Design Qualification Test Report				
Requested by: Craig Ryan Date: 7/2/2013 Product Rev: GP				
Part #: QSE-060-01-F-D-A / QTE-060-01-F-D-A			Tech: Aaron McKim	Eng: Eric Mings
Part description: QSE/QTE Qty to test: 8				
Test Start: 1/10/2013	Test Completed: 2/18/	/2013		





DESIGN QUALIFICATION TEST REPORT

QSE/QTE QSE-060-01-F-D-A / QTE-060-01-F-D-A

Tracking Code: 231303_Report_Rev_2	Part #: QSE-060-01-F-D-A / QTE-060-01-F-D-A			
Part description: OSE/OTE				

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
04/25/2013	1	Initial Issue	PC
07/02/2013	2	Update the cover page	PC

Tracking Code: 231303_Report_Rev_2	Part #: QSE-060-01-F-D-A / QTE-060-01-F-D-A
Pa	rt description: QSE/QTE

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

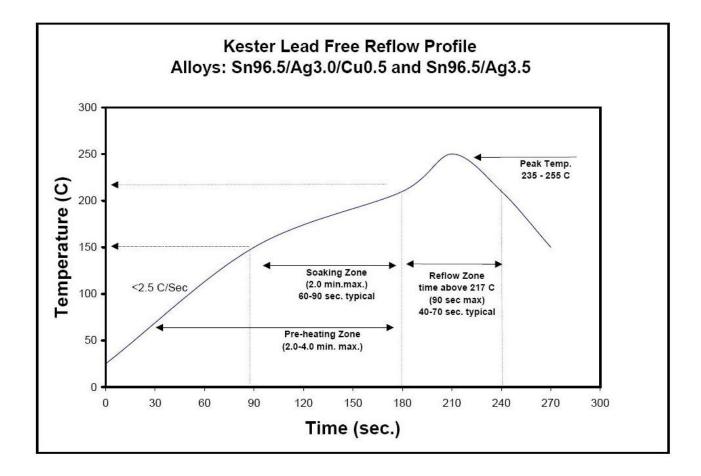
- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) The automated procedure is used with aqueous compatible soldering materials.
- 4) Parts not intended for testing LLCR are visually inspected.
- 5) Any additional preparation will be noted in the individual test sequences.
- 6) Solder Information: Lead Free
- 7) Re-Flow Time/Temp: See accompanying profile.
- 8) Samtec Test PCBs used: PCB-102592-TST-XX

Part #: QSE-060-01-F-D-A / QTE-060-01-F-D-A

Part description: QSE/QTE

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

Tracking Code: 231303_Report_Rev_2



Tracking Code: 231303_Report_Rev_2

Part description: QSE/QTE

FLOWCHARTS

Durability/LLCR

TEST	GROUP A1
STEP	3u" Gold (-F)
	8 Mated Sets
01	LLCR-1
02	10 Cycles
03	LLCR-2
04	Thermal Shock
04	(Mated and Undisturbed)
05	LLCR-3
00	Cyclic Humidity
06	(Mated and Undisturbed)
07	LLCR-4

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25 °C to +65 °C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Tracking Code: 231303_Report_Rev_2	Part #: QSE-060-01-F-D-A / QTE-060-01-F-D-A			
Part description: OSE/OTE				

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.
- 2) Test Condition 1: -55° C to $+85^{\circ}$ C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, Humidity Test Procedure for Electrical Connectors.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

LLCR:

- 1) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. <= +5.0 mOhms:----- Stable b. +5.1 to +10.0 mOhms:---- Minor
 - c. +10.1 to +15.0 mOhms: ----- Acceptable
 - c. +10.1 to +15.0 months: ------ Acceptable
 - d. +15.1 to +50.0 mOhms: ----- Marginal
 - e. +50.1 to +2000 mOhms: ----- Unstable
 - f. >+2000 mOhms:----- Open Failure

RESILTS

CR Dura	ıbility:		
nal pin:	•		
Initial		24.41 mOhms Max	
• Dural	oility, 10 Cycles		
0	<= +5.0 mOhms	192 Points	Stable
0	+5.1 to +10.0 mOhms	0 Points	Minor
0	+10.1 to +15.0 mOhms	0 Points	Acceptable
0	+15.1 to +50.0 mOhms	0 Points	Marginal
0	+50.1 to +2000 mOhms	0 Points	Unstable
0	>+2000 mOhms	0 Points	Open Failu
• Thern	nal Shock		_
0	<= +5.0 mOhms	192 Points	Stable
0	+5.1 to +10.0 mOhms	0 Points	Minor
0	+10.1 to +15.0 mOhms	0 Points	Acceptable
0	+15.1 to +50.0 mOhms	0 Points	Marginal
0	+50.1 to +2000 mOhms	0 Points	Unstable
0	>+2000 mOhms	0 Points	Open Failu
• Humi	dity		•
0	<= +5.0 mOhms	192 Points	Stable
0	+5.1 to +10.0 mOhms		
0	+10.1 to +15.0 mOhms	0 Points	Acceptable
0	+15.1 to +50.0 mOhms	0 Points	Marginal
0			U
0	+15.1 to +50.0 mOhms +50.1 to +2000 mOhms> >+2000 mOhms	0 Points	Unstable
ound pin: Initial	+50.1 to +2000 mOhms>+2000 mOhms	0 Points 0 Points	Unstable
ound pin: Initial	+50.1 to +2000 mOhms>+2000 mOhms	0 Points 0 Points	Unstable
ound pin: Initial	+50.1 to +2000 mOhms	0 Points0 Points	Unstable Open Failu Stable
ound pin: Initial • Dural	+50.1 to +2000 mOhms>+2000 mOhms	0 Points0 Points	Unstable Open Failu Stable
ound pin: Initial • Dural	+50.1 to +2000 mOhms	0 Points0 Points	Unstable Open Failu Stable Minor
ound pin: Initial • Dural	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable
ound pin: Initial • Dural	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal
ound pin: Initial Dural	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal
ound pin: Initial Dural O	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable
ound pin: Initial Dural O	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable
ound pin: Initial Dural Output Therm	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable Open Failu Stable
ound pin: Initial Dural Output Therm	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Marginal Unstable Open Failu Stable Acceptable
ound pin: Initial Dural Output Therm Output O	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Marginal Unstable Open Failu Stable Acceptable
ound pin: Initial Dural Output Therm Output O	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable Open Failu Stable Minor Minor Acceptable Minor Acceptable Marginal
ound pin: Initial Dural Therm Therm	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable Open Failu Stable Minor Minor Acceptable Minor Acceptable Marginal
ound pin: Initial Dural Output Therm Output O	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Marginal Unstable Open Failu Stable Minor Minor Acceptable Minor Acceptable Marginal
ound pin: Initial Dural Therm Therm	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Unstable Open Failu Stable Minor Acceptable Marginal Unstable Marginal Unstable Unstable Stable
ound pin: Initial Dural Therm Humi	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Unstable Open Failu Stable Minor Acceptable Marginal Unstable Den Failu Stable Unstable Unstable Open Failu
ound pin: Initial Dural Therr Humi	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Unstable Open Failu Stable Acceptable Marginal Acceptable Marginal Unstable Copen Failu Open Failu Open Failu Open Failu Open Failu
ound pin: Initial Dural Therr Humi	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Unstable Open Failu Stable Acceptable Marginal Acceptable Den Failu Stable Acceptable Open Failu Open Failu Open Failu Minor Acceptable Minor
ound pin: Initial Dural Therm Humi	+50.1 to +2000 mOhms		Unstable Open Failu Stable Minor Acceptable Unstable Open Failu Stable Acceptable Marginal Acceptable Den Failu Stable Open Failu Open Failu Open Failu Acceptable Minor Acceptable

Tracking Code: 231303_Report_Rev_2

Part description: QSE/QTE

DATA SUMMARIES

LLCR Durability:

- 1) A total of 192 points were measured.
- 2) EIA-364-23, Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.

a. <= +5.0 mOhms:----- Stable b. +5.1 to +10.0 mOhms:---- Minor

c. +10.1 to +15.0 mOhms: ----- Acceptable

d. +15.1 to +50.0 mOhms: ----- Marginal

e. +50.1 to +2000 mOhms ----- Unstable

f. >+2000 mOhms: ----- Open Failure

	LLCR Measurement Summaries by Pin Type				
Date	1/10/2013	1/18/2013	2/4/2013	2/18/2013	
Room Temp (Deg C)	22	22	22	22	
Rel Humidity (%)	31	32	34	33	
	Aaron	Aaron		Aaron	
Technician	McKim	McKim	Aaron McKim	McKim	
mOhm values	Actual	Delta	Delta	Delta	
	Initial	10 Cycles	Therm Shck	Humidity	
		Pin Typ	e 1: Signal		
Average	22.24	0.73	0.60	0.63	
St. Dev.	0.81	0.54	0.45	0.51	
Min	19.92	0.00	0.00	0.00	
Max	24.41	2.42	1.97	2.79	
Summary Count	168	168	168	168	
Total Count	168	168	168	168	
		Pin Type	e 2: Ground		
Average	1.50	0.05	0.07	0.09	
St. Dev.	0.07	0.04	0.05	0.06	
Min	1.37	0.00	0.00	0.00	
Max	1.60	0.15	0.20	0.23	
Summary Count	24	24	24	24	
Total Count	24	24	24	24	

LLCR Delta Count by Category						
	Stable Minor Acceptable Marginal Unstable Op					
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
10 Cycles	192	0	0	0	0	0
Therm Shck	192	0	0	0	0	0
Humidity	192	0	0	0	0	0

Part description: QSE/QTE

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: MO-04

Description: Multimeter /Data Acquisition System

Manufacturer: Keithley

Model: 2700 Serial #: 0798688 Accuracy: See Manual

... Last Cal: 04/30/2013, Next Cal: 04/30/2014

Equipment #: THC-02

Description: Temperature/Humidity Chamber

Manufacturer: Thermotron

Model: SE-1000-6-6 **Serial #:** 31808

Accuracy: See Manual

... Last Cal: 02/16/2013, Next Cal: 02/16/2014

Equipment #: TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnatti Sub Zero

Model: VTS-3-6-6-SC/AC Serial #: 10-VT14993 Accuracy: See Manual

... Last Cal: 05/18/2013, Next Cal: 05/18/2014